

Silicon Detectors

Gabriele Giacomini

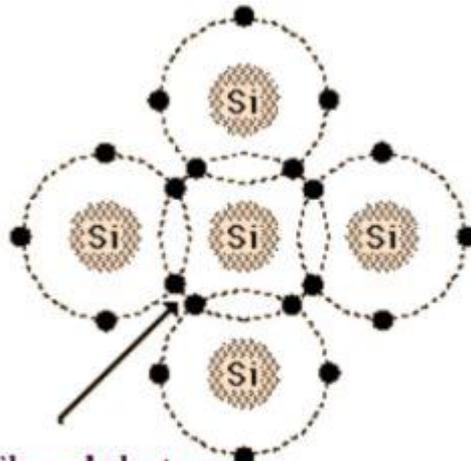
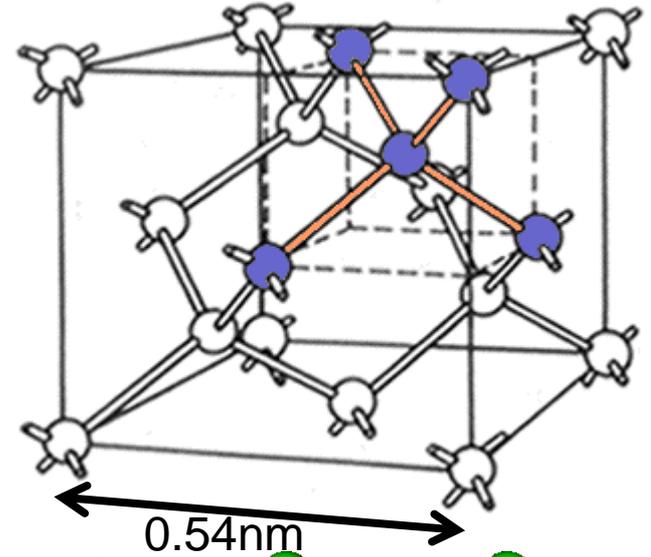
BROOKHAVEN
NATIONAL LABORATORY



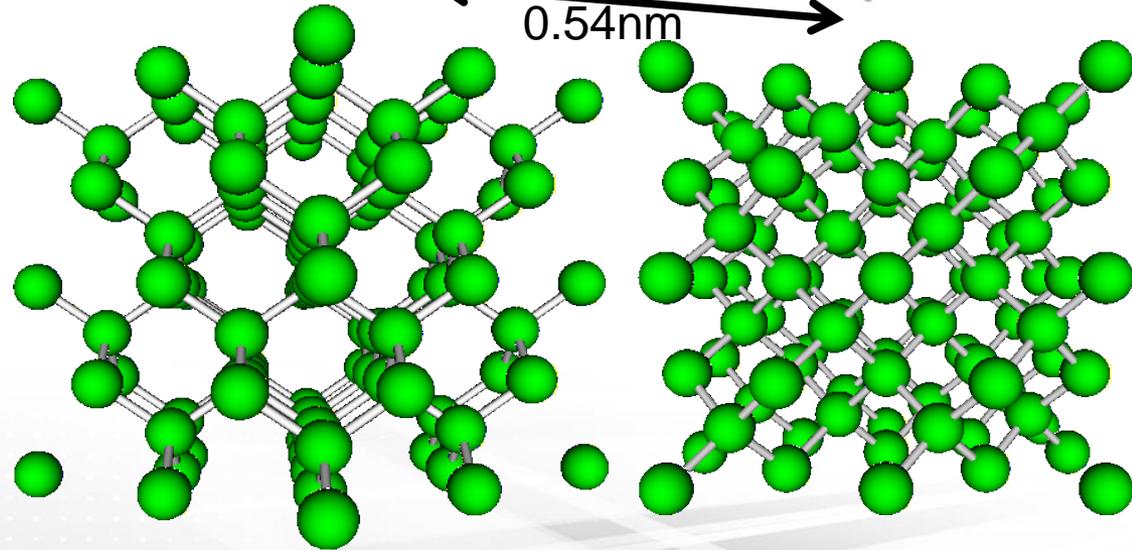
The silicon crystal

Group	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	
1	1 H																		2 He
2	3 Li	4 Be											5 B	6 C	7 N	8 O	9 F	10 Ne	
3	11 Na	12 Mg											13 Al	14 Si	15 P	16 S	17 Cl	18 Ar	
4	19 K	20 Ca	21 Sc	22 Ti	23 V	24 Cr	25 Mn	26 Fe	27 Co	28 Ni	29 Cu	30 Zn	31 Ga	32 Ge	33 As	34 Se	35 Br	36 Kr	
5	37 Rb	38 Sr	39 Y	40 Zr	41 Nb	42 Mo	43 Tc	44 Ru	45 Rh	46 Pd	47 Ag	48 Cd	49 In	50 Sn	51 Sb	52 Te	53 I	54 Xe	
6	55 Cs	56 Ba	57 La*	72 Hf	73 Ta	74 W	75 Re	76 Os	77 Ir	78 Pt	79 Au	80 Hg	81 Tl	82 Pb	83 Bi	84 Po	85 At	86 Rn	
7	87 Fr	88 Ra	89 Ac*	104 Rf	105 Db	106 Sg	107 Bh	108 Hs	109 Mt	110 Ds	111 Rg	112 Cn	113 Nh	114 Fl	115 Mc	116 Lv	117 Ts	118 Og	
				58 Ce	59 Pr	60 Nd	61 Pm	62 Sm	63 Eu	64 Gd	65 Tb	66 Dy	67 Ho	68 Er	69 Tm	70 Yb	71 Lu		
				90 Th	91 Pa	92 U	93 Np	94 Pu	95 Am	96 Cm	97 Bk	98 Cf	99 Es	100 Fm	101 Md	102 No	103 Lr		

Diamond structure (tetrahedron)
Unit cell has 8 atoms

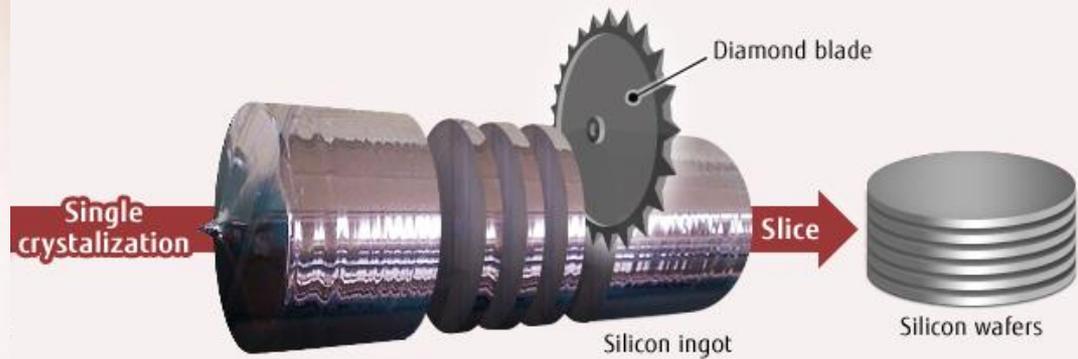
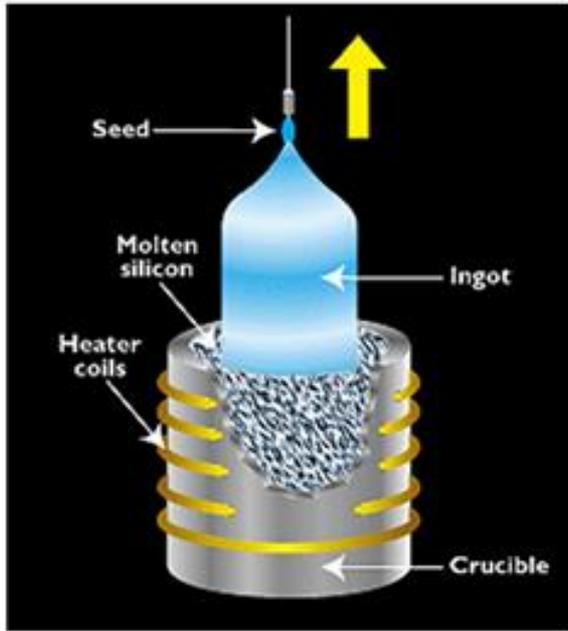
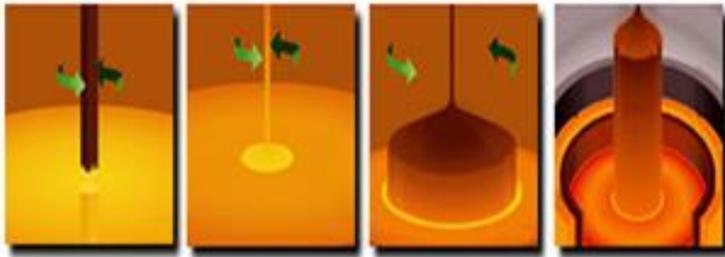


Shared electrons
in covalent
bond



110

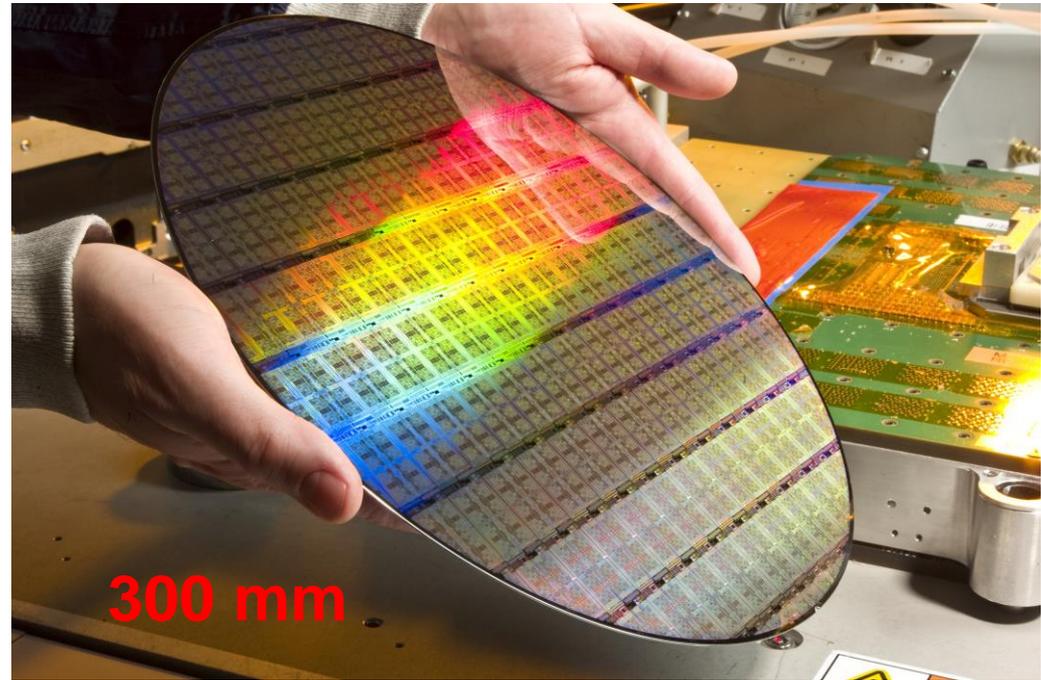
100



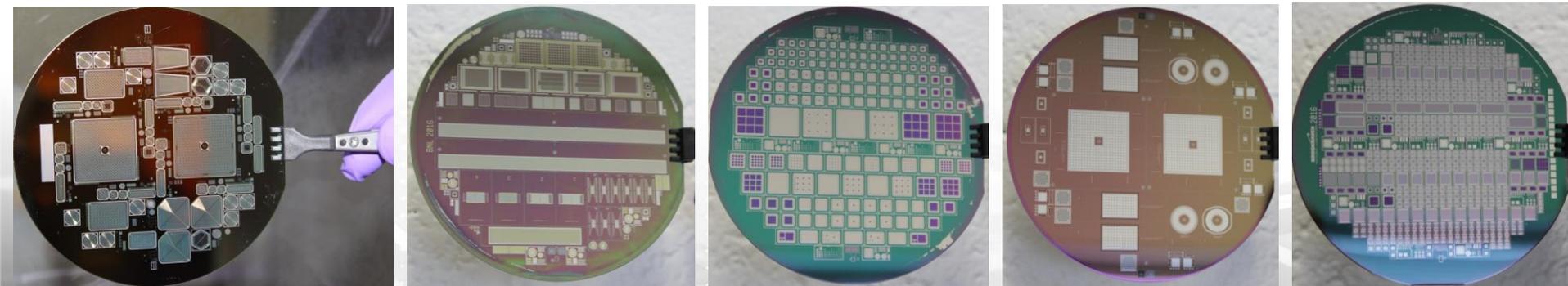
Silicon wafers as you can buy



Integrated Circuits (IC) on a Silicon wafer



4" (10-cm) silicon wafer processed at BNL



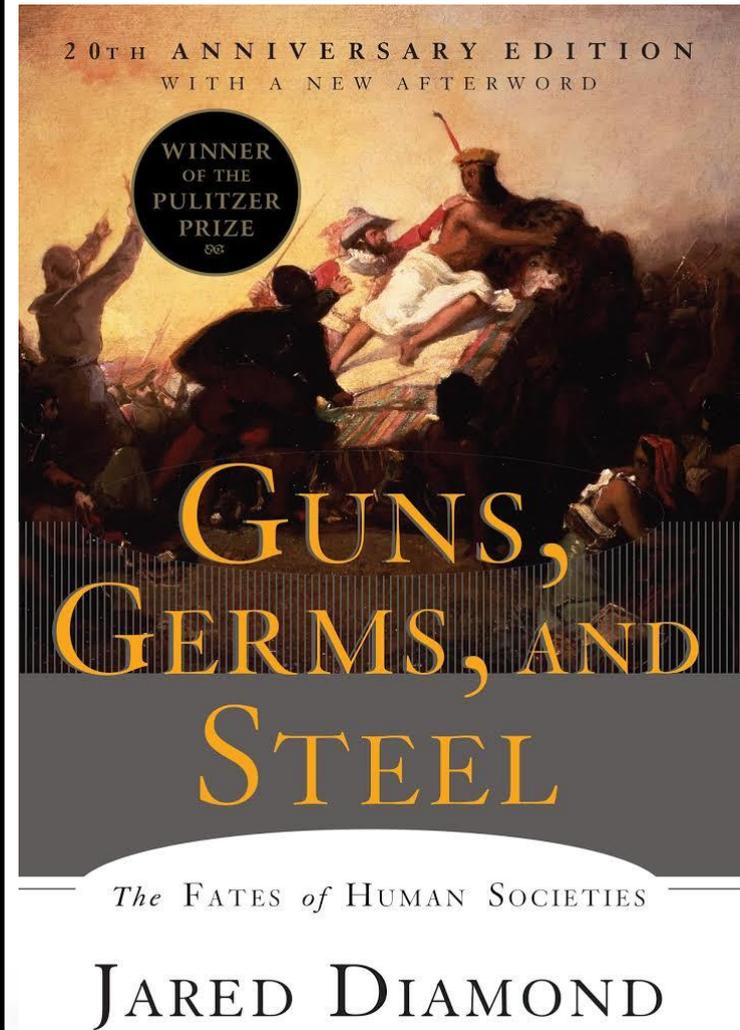
Two great materials: Silicon vs Steel



A VIEW TO A KILL



Max Zorin: “For centuries alchemists tried to make gold from base metals. Today, we make microchips from silicon, which is common sand, but far better than gold”



Two great materials: Silicon vs Steel

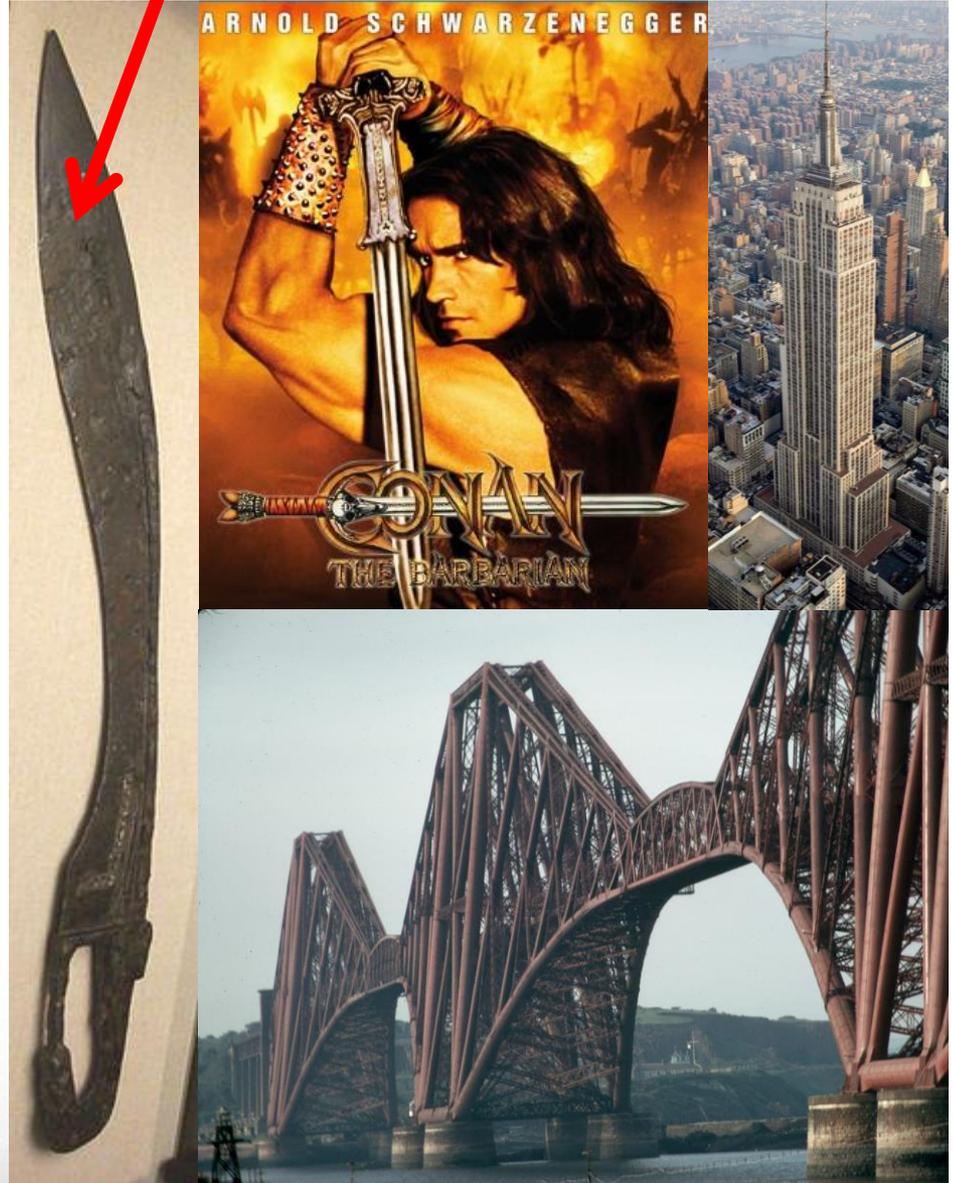
Shockley, Bardeen, Brattain 1950



Moore, Noyce, Grove at Intel 1978

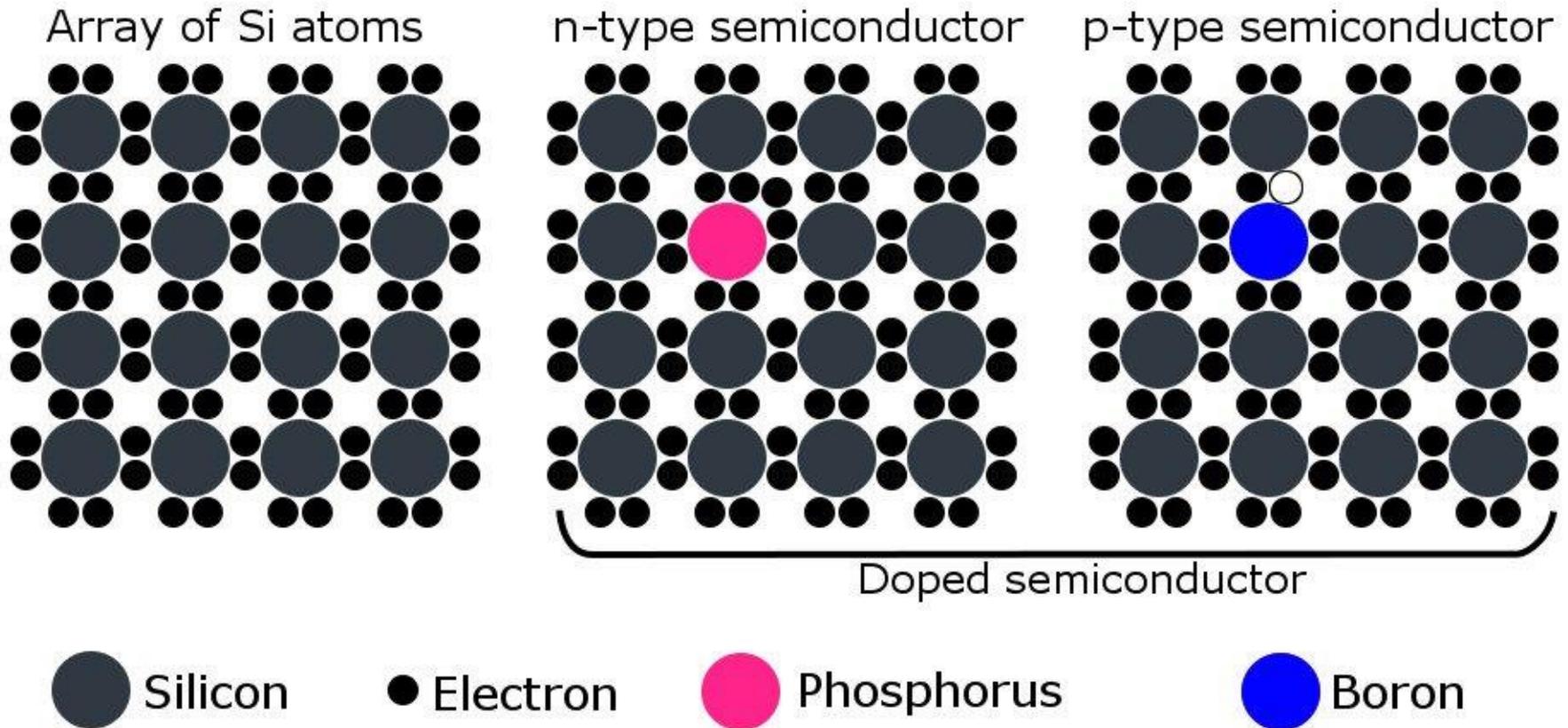


Falcata (4th century BC)

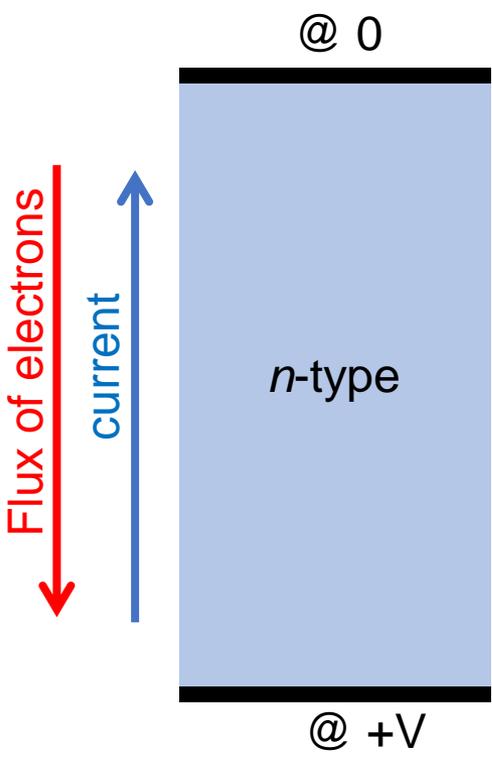


Electrons and holes

Doping in Semiconductors

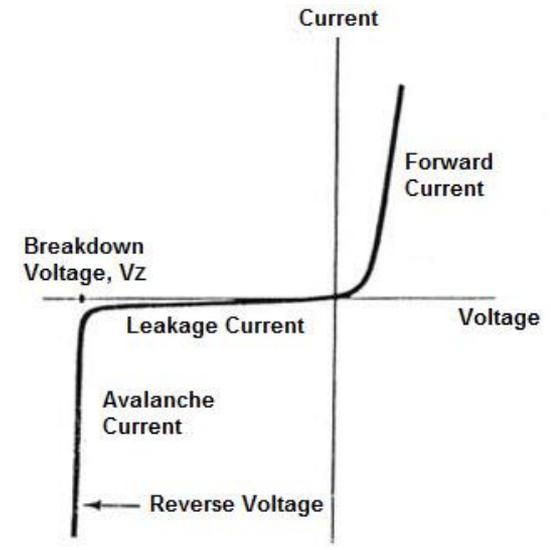
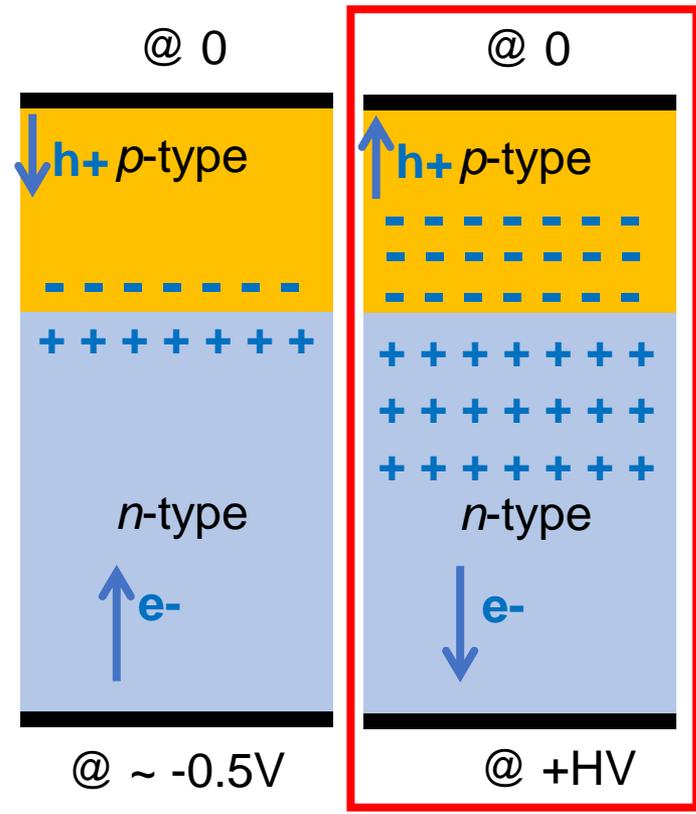


n-type silicon slab:
essentially a resistor



$dE/dx = -\rho/\epsilon$
 Since charge neutrality holds ($\rho=0$),
 $E = \text{constant} = V/\text{thickness}$

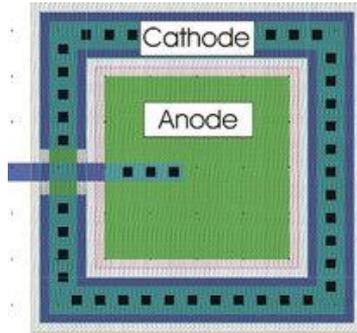
n-type slab + *p*-type slab = Rectifying junction (diode)



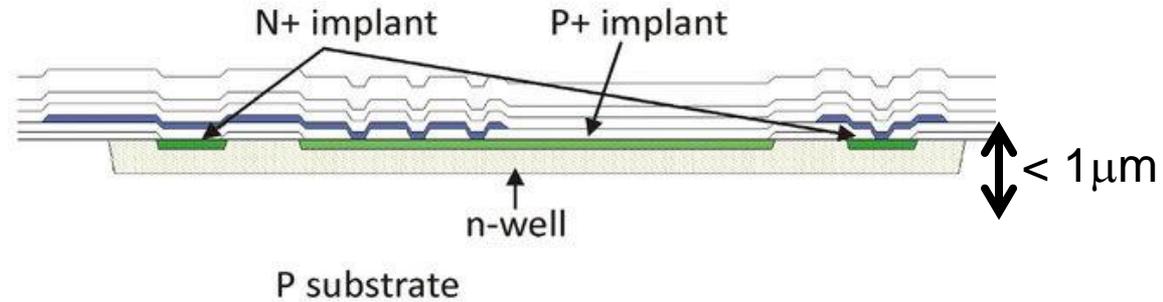
In forward bias, high currents flow.
 In reverse bias, the current is blocked, so the Voltage must fall in a region with $\rho \neq 0$:
 Electrons (holes) are swept away from *n*- (*p*-) type silicon leaving a net positive (negative) charge,

Diode in integrated circuits

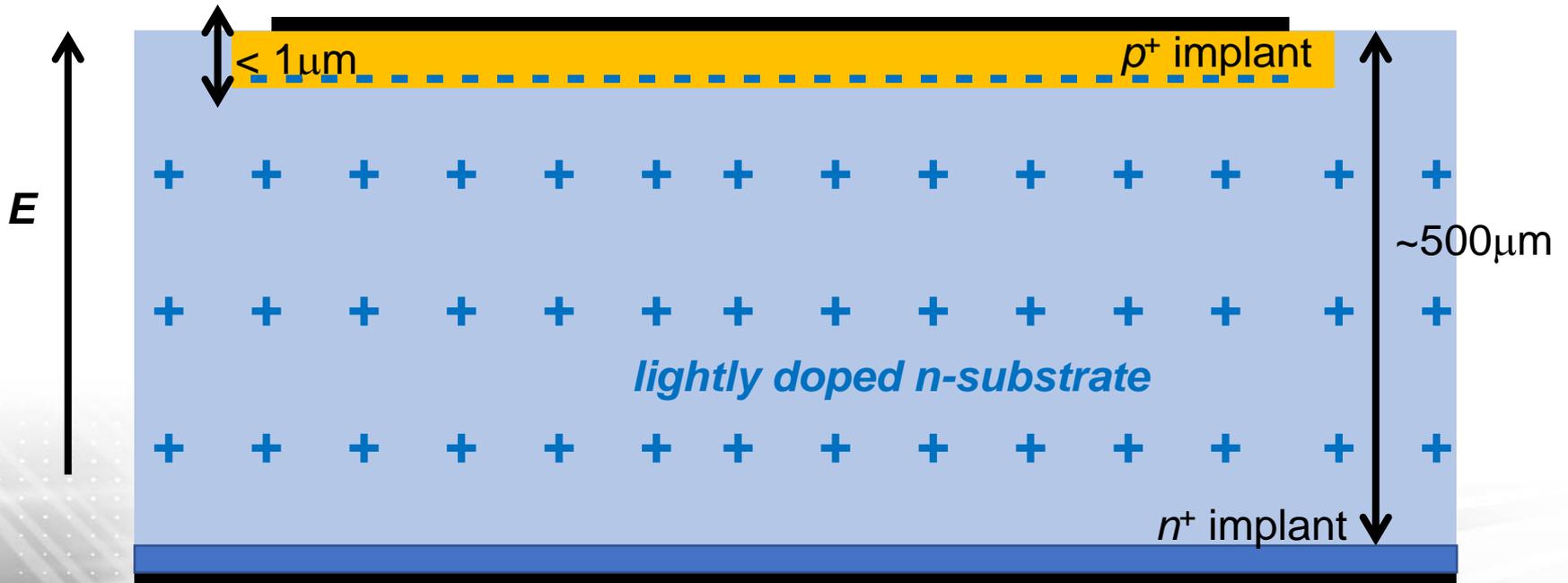
From the top



Section

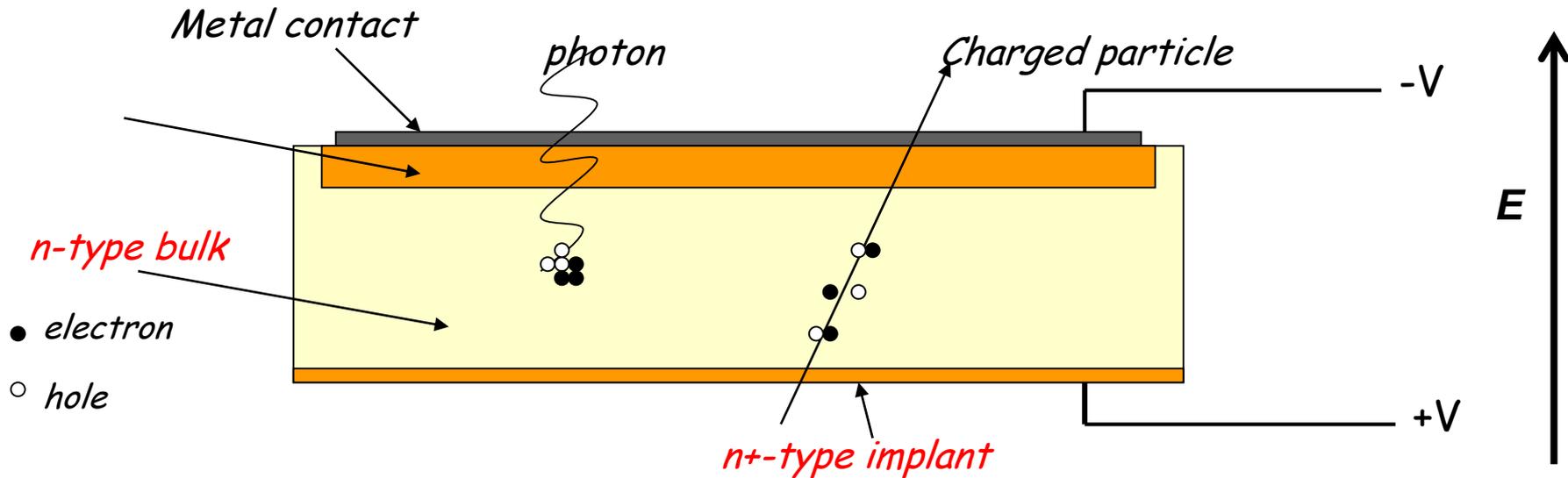


Diode as a sensor unit



Mechanism of radiation detection

Ionizing radiation (photons or charged particles) creates free charges in the bulk. Electrons and holes drift in opposite directions, following the electric field lines, creating current pulses at the electrodes

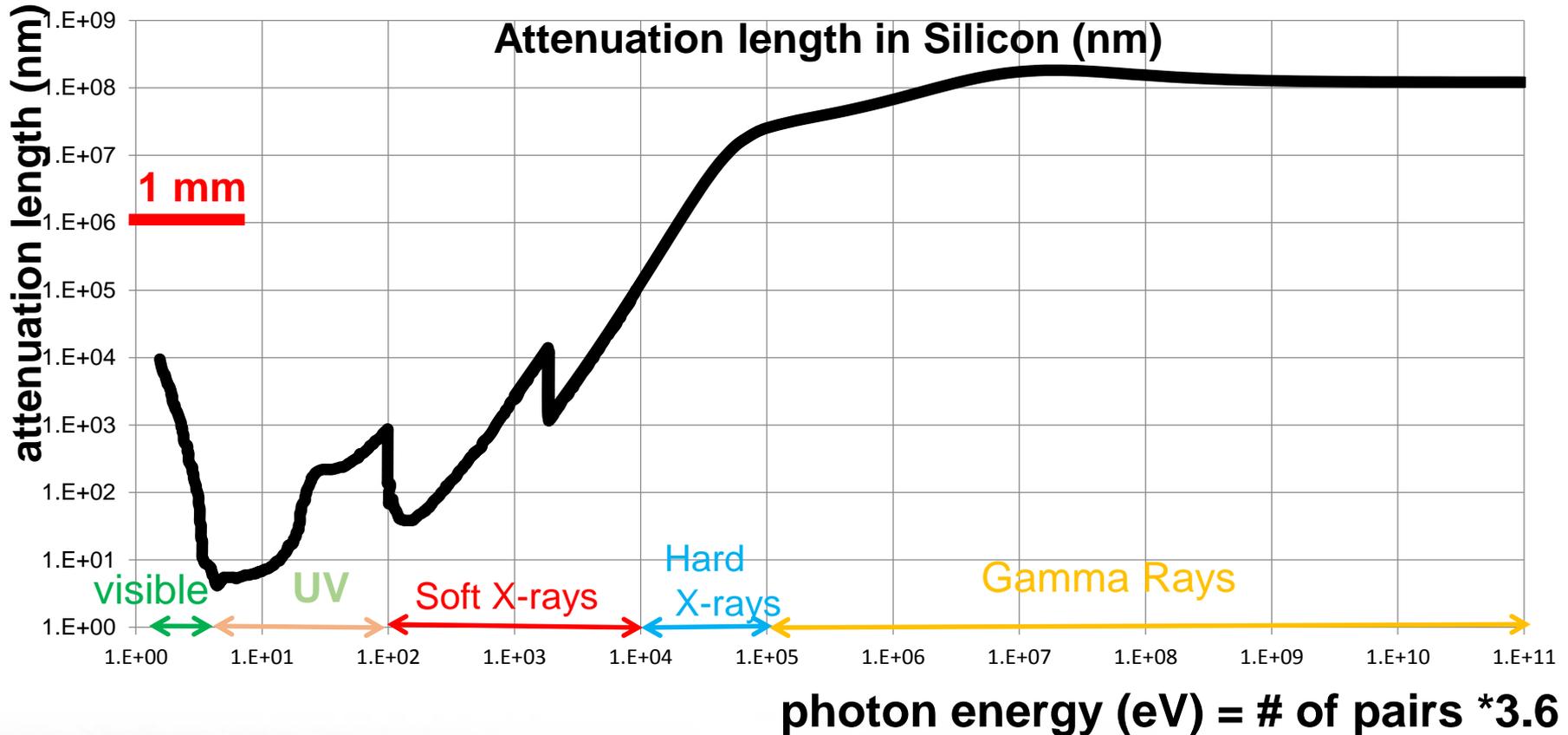


Why sensors made of silicon?

- Very well developed technology (simplified version of IC's)
- Fair signals created, “easily” detected (3.6 eV for the creation of an electron/hole pair)
- Operation close to Room Temperature (RT)
- Possibility to finely segment the electrodes down to few tens of μm

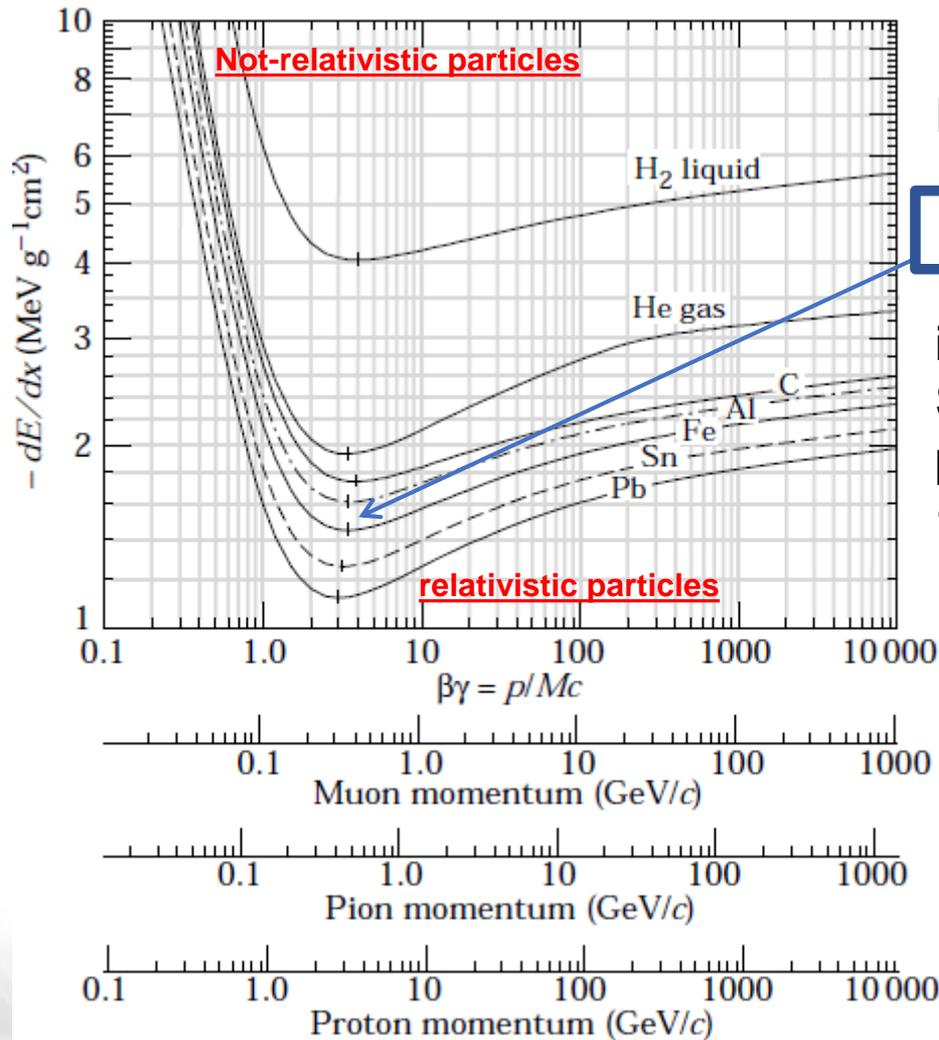
Absorption of photons in Silicon

If N_0 photons enter the silicon, after a distance L , the number of photons which have not been absorbed by silicon is: $N = N_0 \exp(-L/l)$, where l is the attenuation length



- Silicon detects with good efficiency above 20 eV and below 20 keV
- Visible photons create just one couple e^-/h^+

Interaction of charged particles with silicon: the Bethe Block formula



In most practical cases,

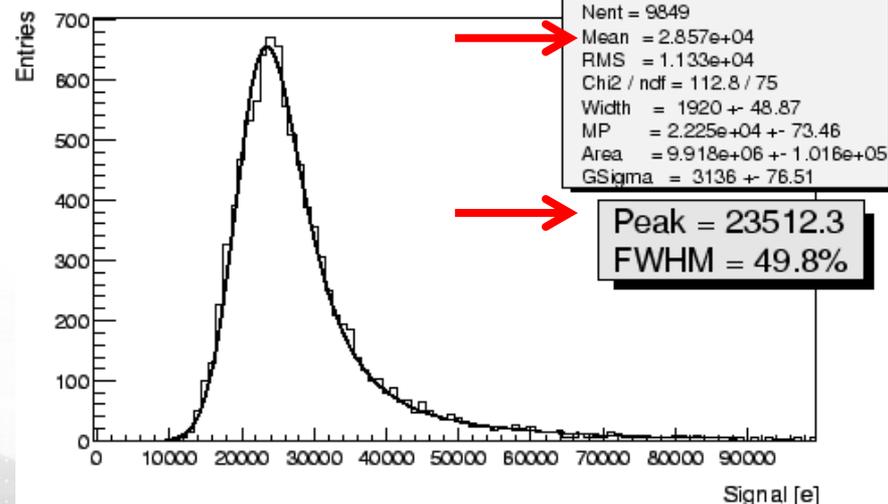
we are here

i.e. at the minimum of energy loss.

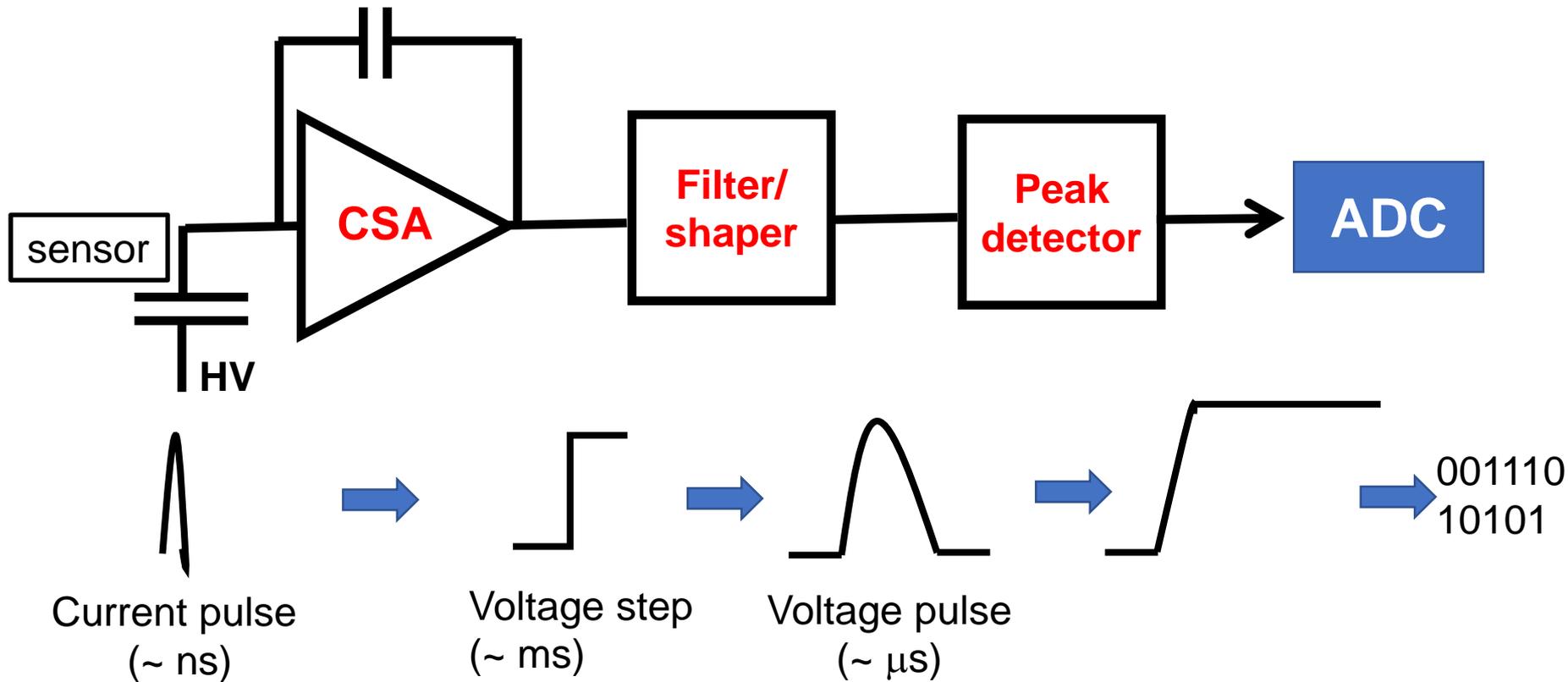
Still, a **m.i.p.** (minimum ionizing particle) produces 80 pairs/ μm in Silicon (for 300 μm \rightarrow 24k electrons)

Landau distribution

Signal distribution in 300 μm silicon

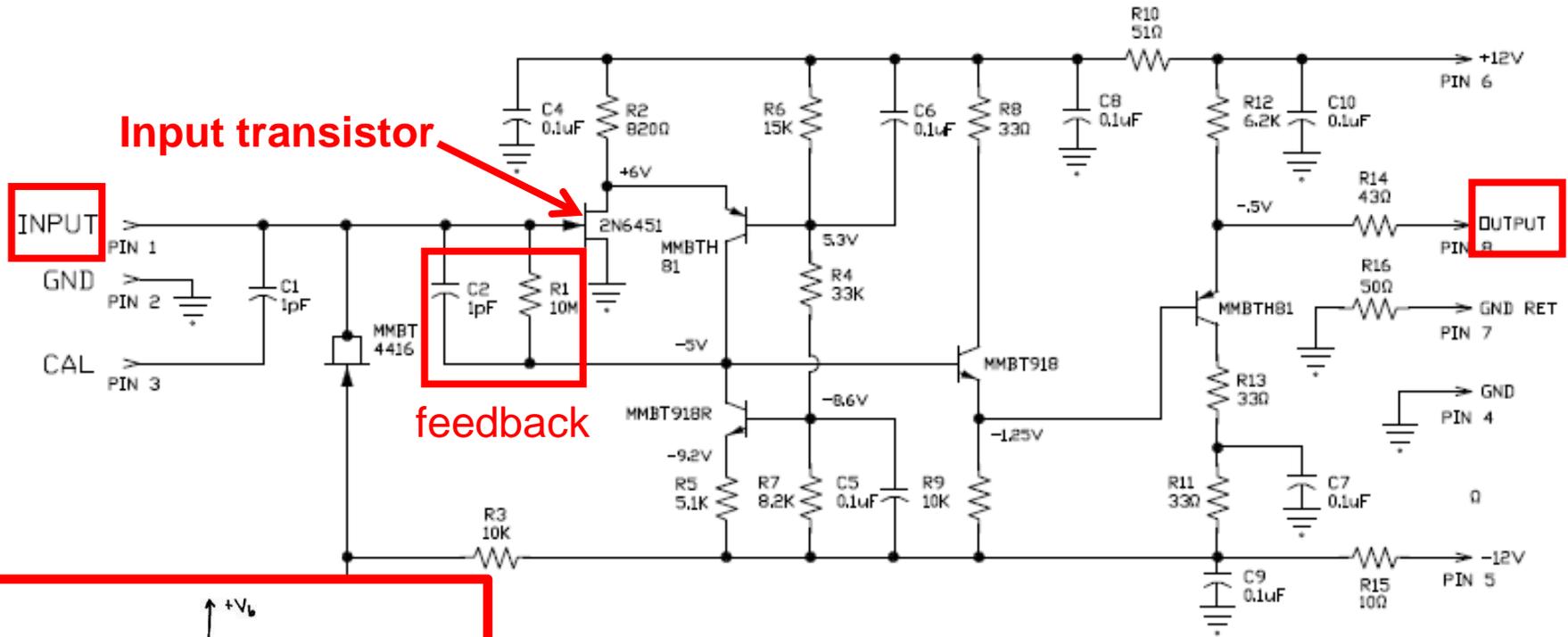


Read-out chain



- Can be made by separate blocks
- Modern trend: integrate everything in a IC
 - ASIC: Application Specific Integrated Circuit, designed in house but fabricated in TSMC, IBM, AMS, ST, ...

Charge Sensitive Pre-Amplifier

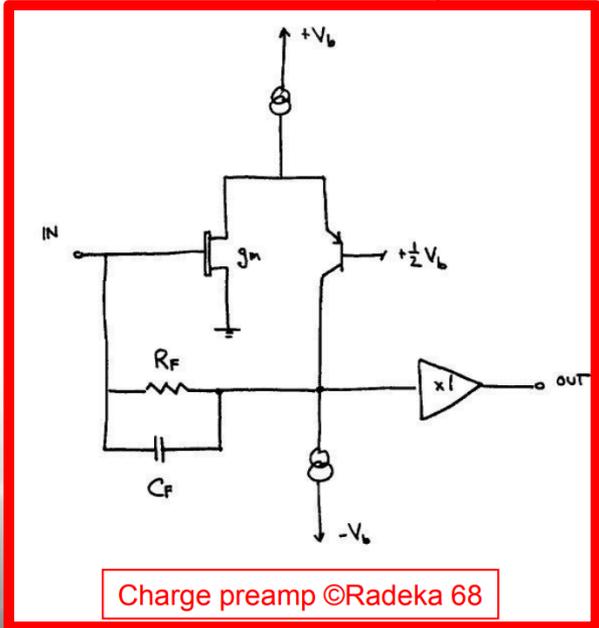


Input transistor

INPUT

feedback

OUTPUT



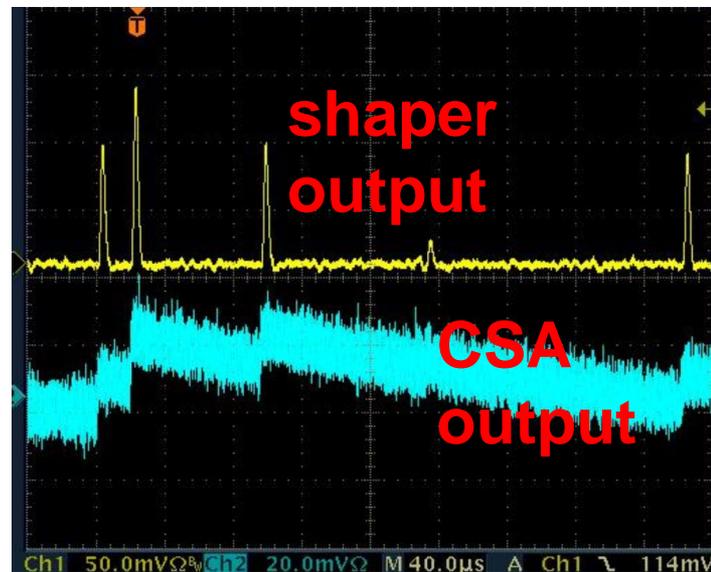
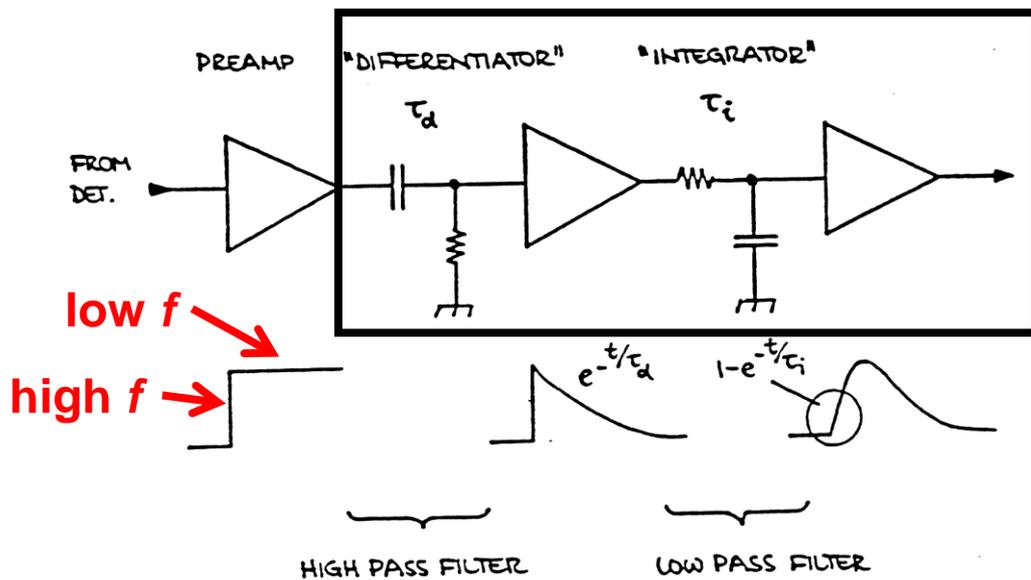
Charge preamp ©Radeka 68

Double source-follower stage

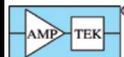


The common trend is to fabricate the CSA in CMOS technology: smaller, good electrical properties, cheap. For example, state-of-the-art is CUBE $\sim 1 \times 1 \times 1 \text{ mm}^3$

Filter/shaper



- **Filtering** in the frequency domain = **Shaping** in the time domain
- Limit the bandwidth to limit the noise
- Noise depends on shaping time
- Modern trend: to go from analog to digital shaping



Digital Pulse Processor, MCA and Power Supply

PX5

Features

- Includes digital pulse shaping amplifier, MCA, and power supplies
- Compatible with all Amptek SDD, Si-PIN, and CdTe-diode detectors
- Supports detectors from other manufacturers, and both reset and feedback preamplifiers of either polarity
- Highly configurable
- Trapezoidal, and new Cusp shaping with wide range of peaking times to optimize performance
- High count rate capability with excellent baseline stability, throughput, and pile-up rejection
- Up to 8k output MCA channels
- Oscilloscope mode - DAC output monitoring and adjustment

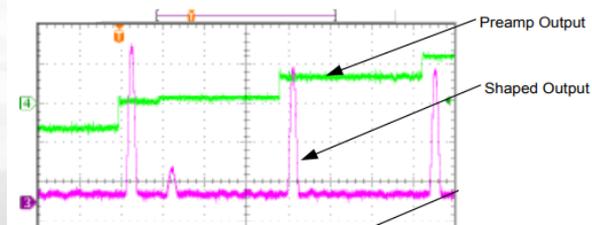


Front



PX5 Waveforms

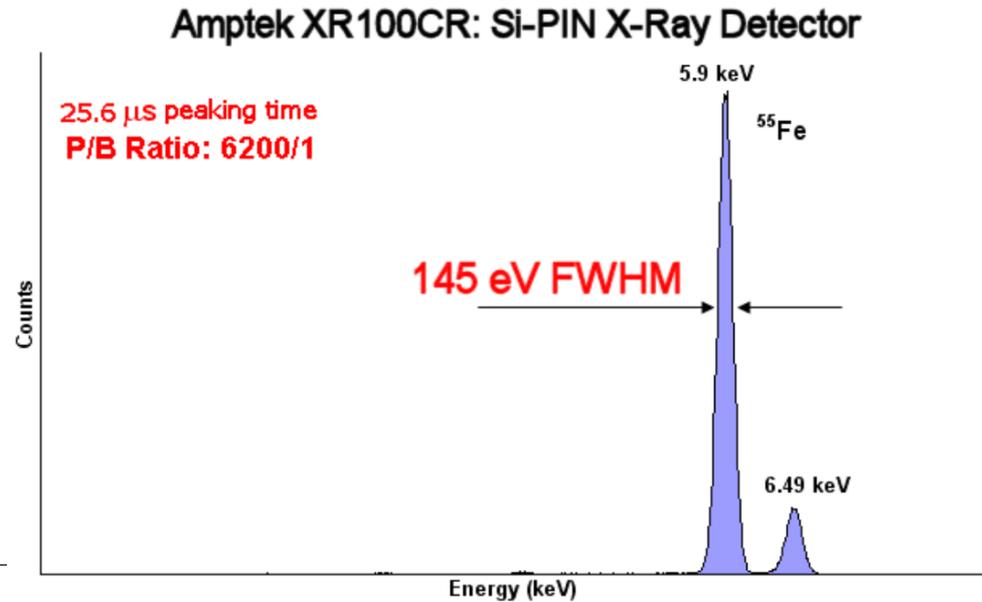
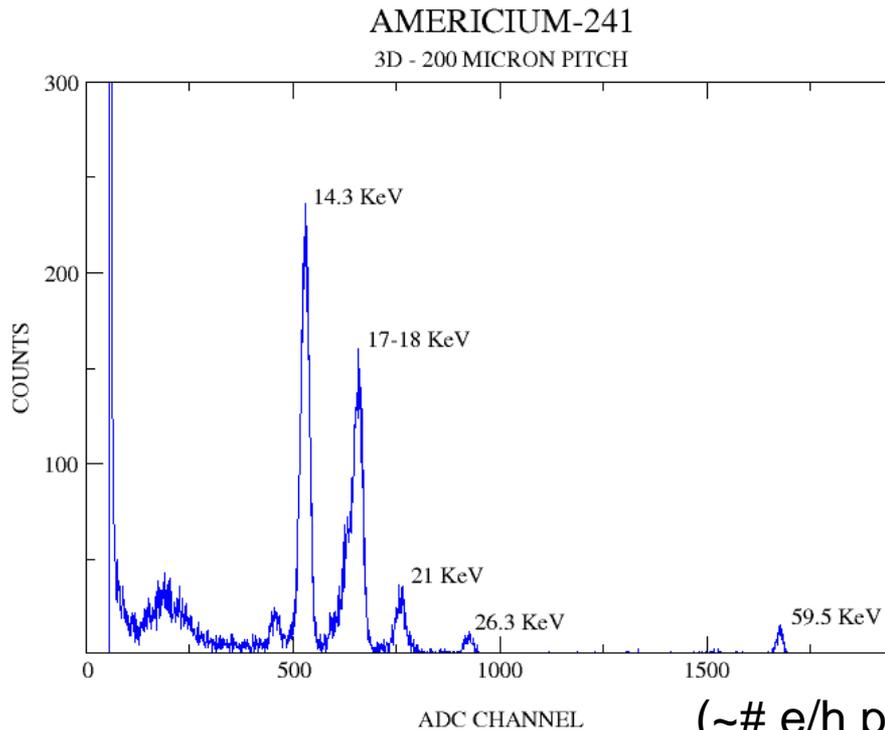
PX5 waveforms, showing from the preamp output to the shaped pulse etc.



Peak detection

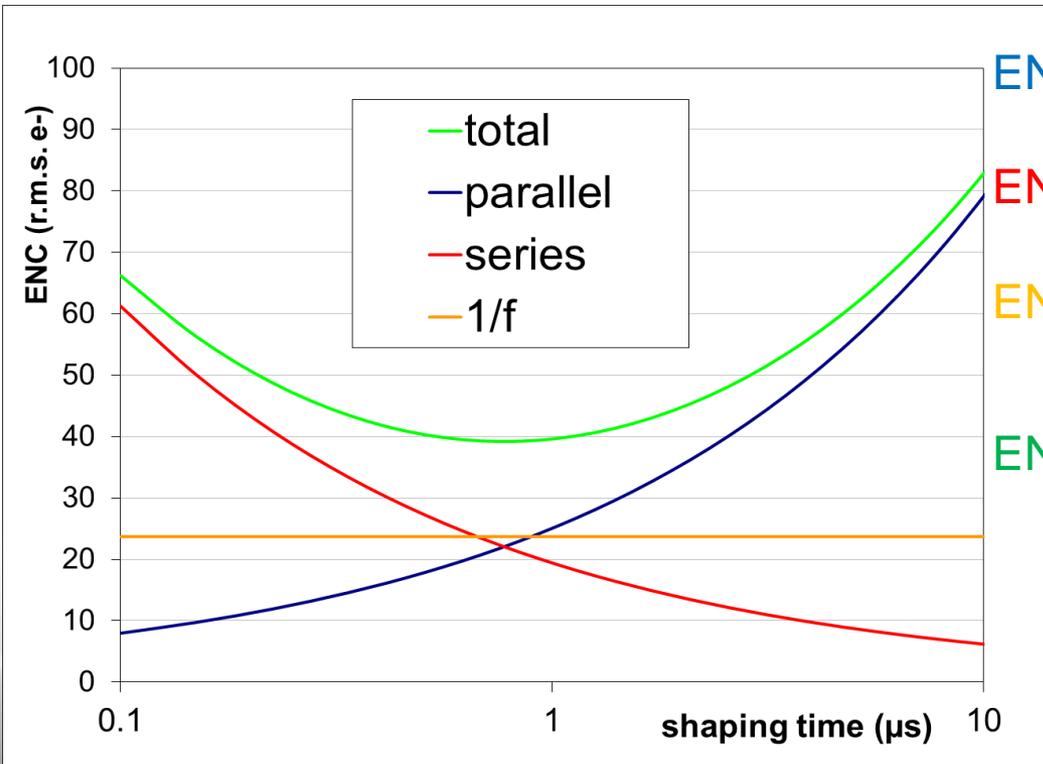
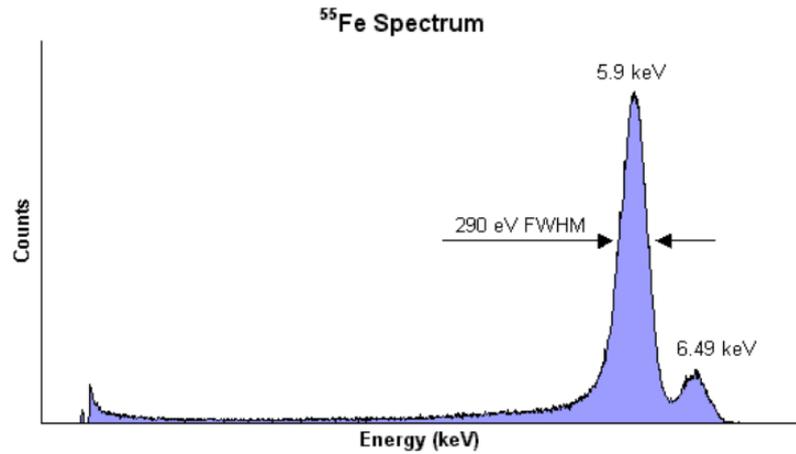
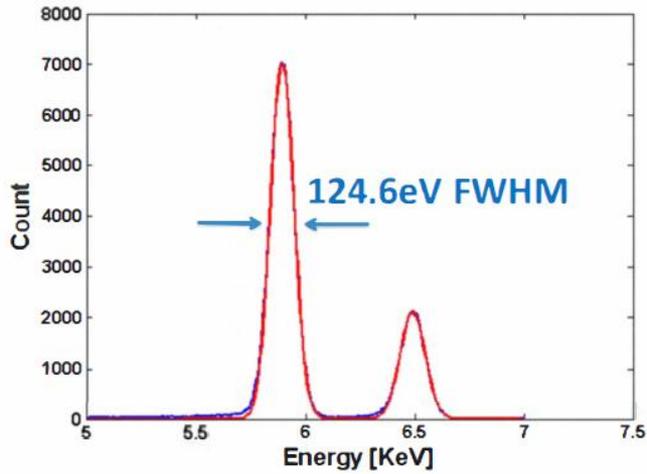
electron/hole pairs ~ amplitude of CSA output ~ amplitude of shaper output.

Stored for a short period of time, then fed to Analog-to-Digital Converter.
Then sent out for processing



Low-activity X-ray-emitting radioactive materials are used as calibration sources

Noise in a detection system



$$ENC^2_{\text{parallel}} \sim I_{\text{leakage}} \tau$$

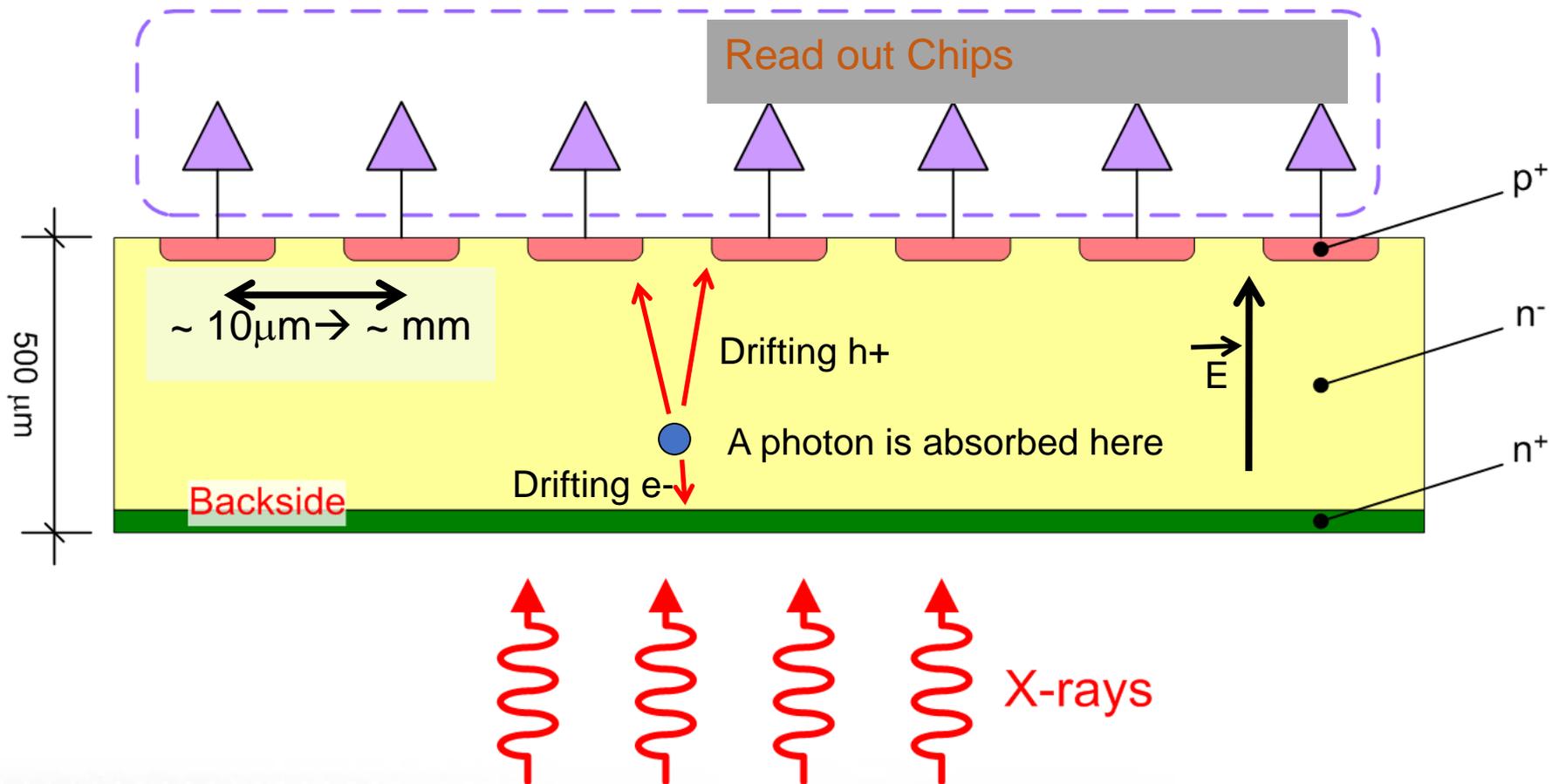
$$ENC^2_{\text{series}} \sim C^2 / \tau$$

$$ENC_{\text{flicker}} \sim \text{constant}$$

$$ENC^2_{\text{total}} = ENC^2_{\text{parallel}} + ENC^2_{\text{series}} + ENC^2_{\text{flicker}}$$

Patterning the electrodes

It gives information about the position of the incident radiation

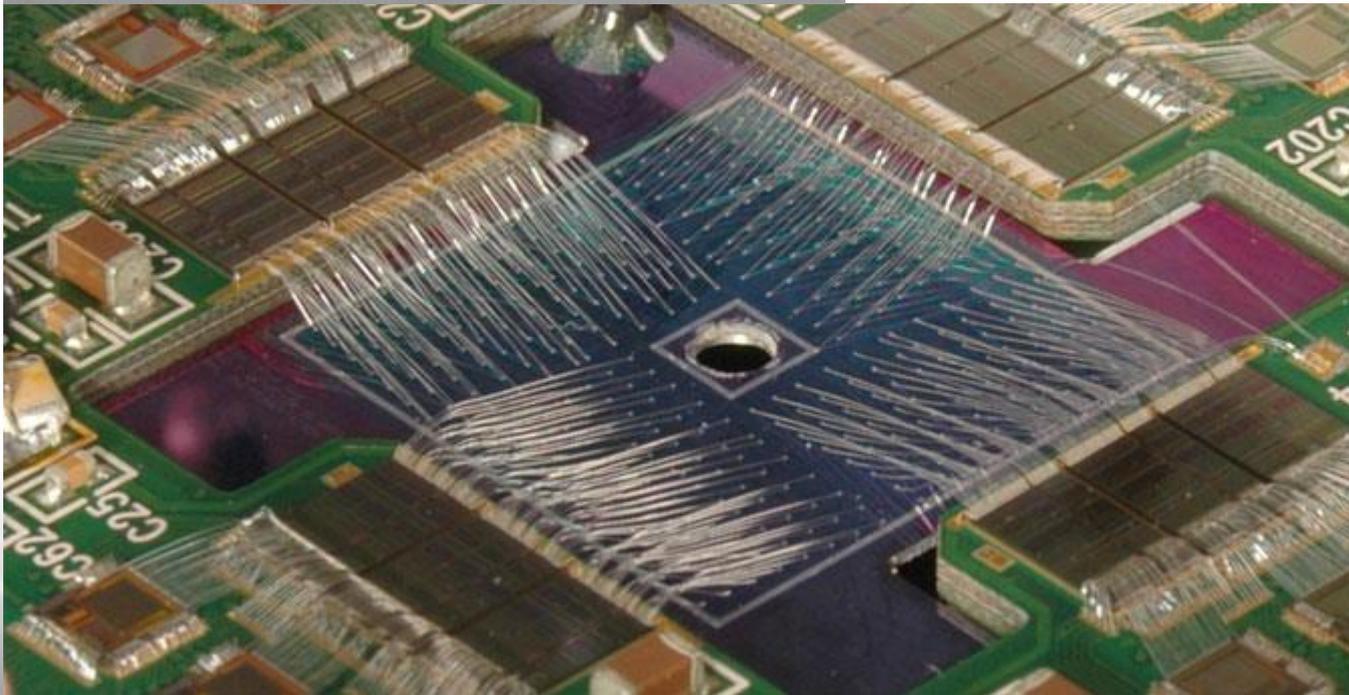
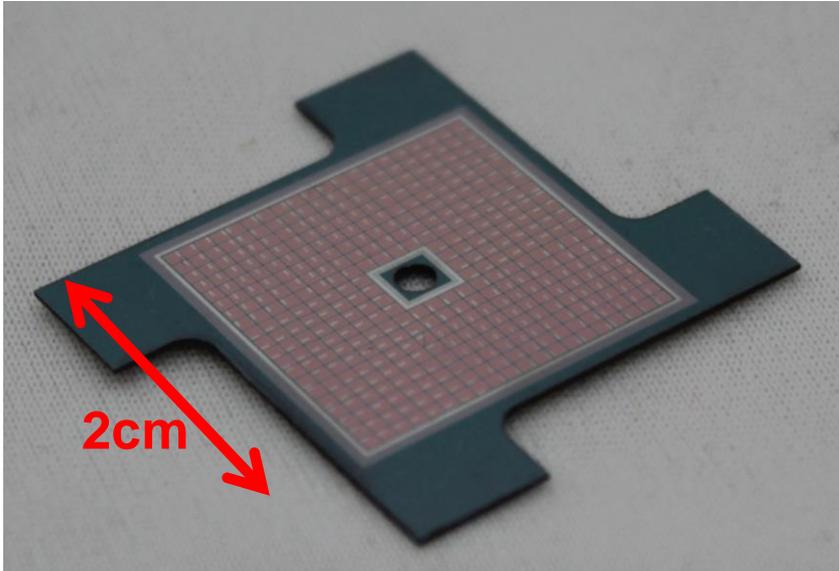


Pixels, pads, strip are possible, in a large variety of dimensions, ranging from few μm to mm , depending on the application

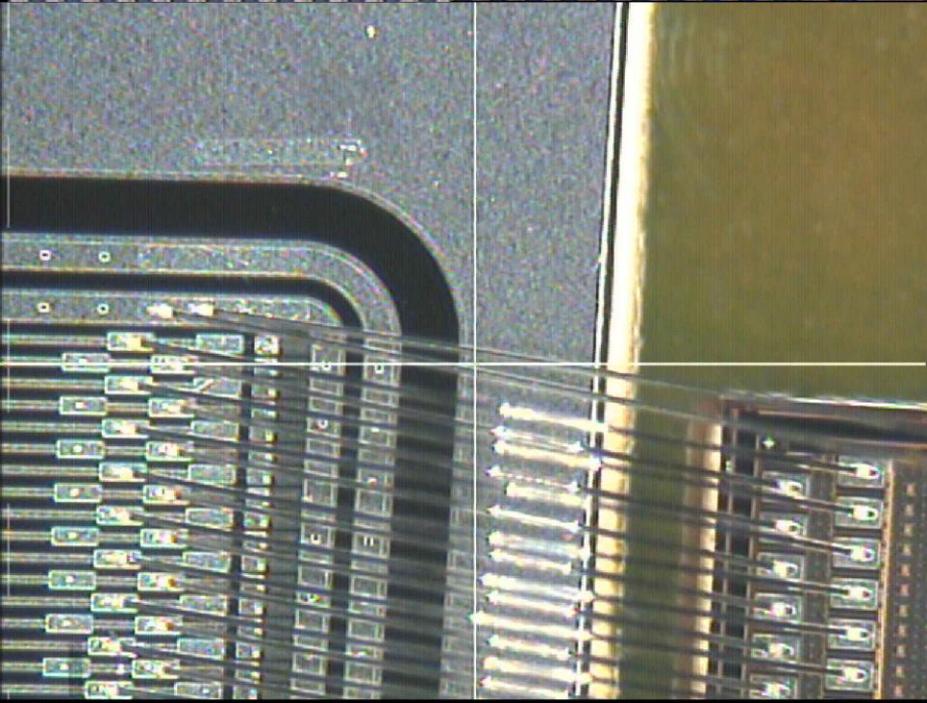
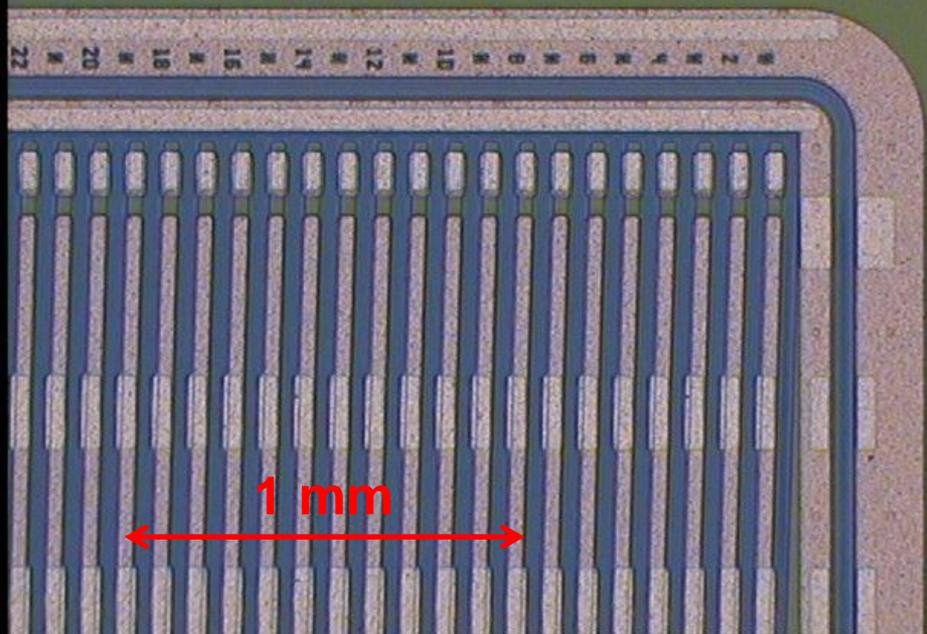
Pad sensor

Array of ~ 400 square pads
at a pitch of 1 mm

MAIA microprobe detector for elemental
analysis in synchrotrons



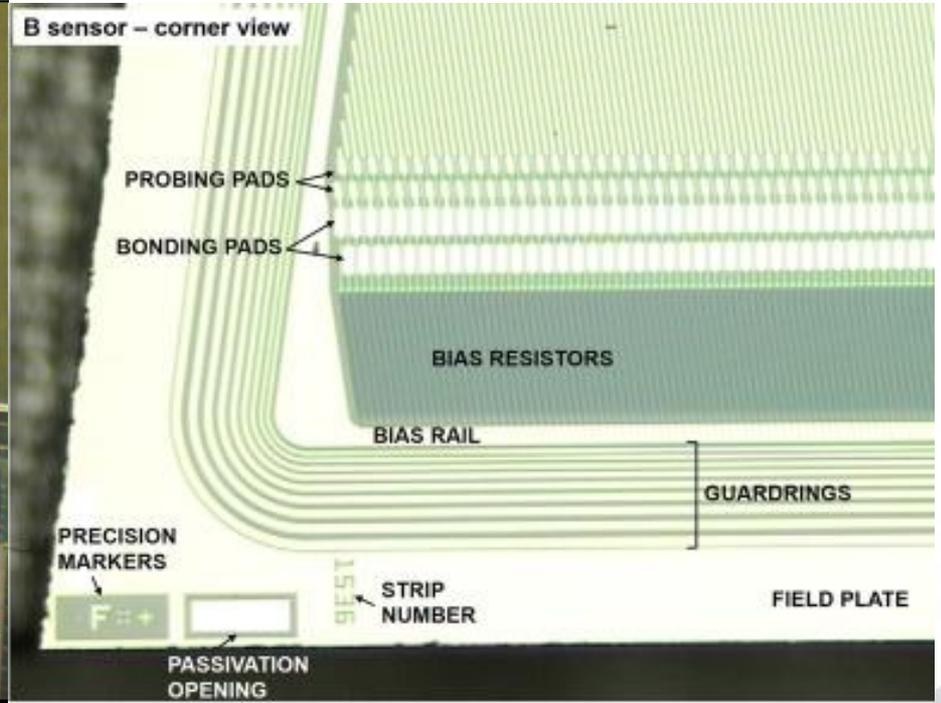
Microstrip for ALICE at CERN



Microstrip sensors

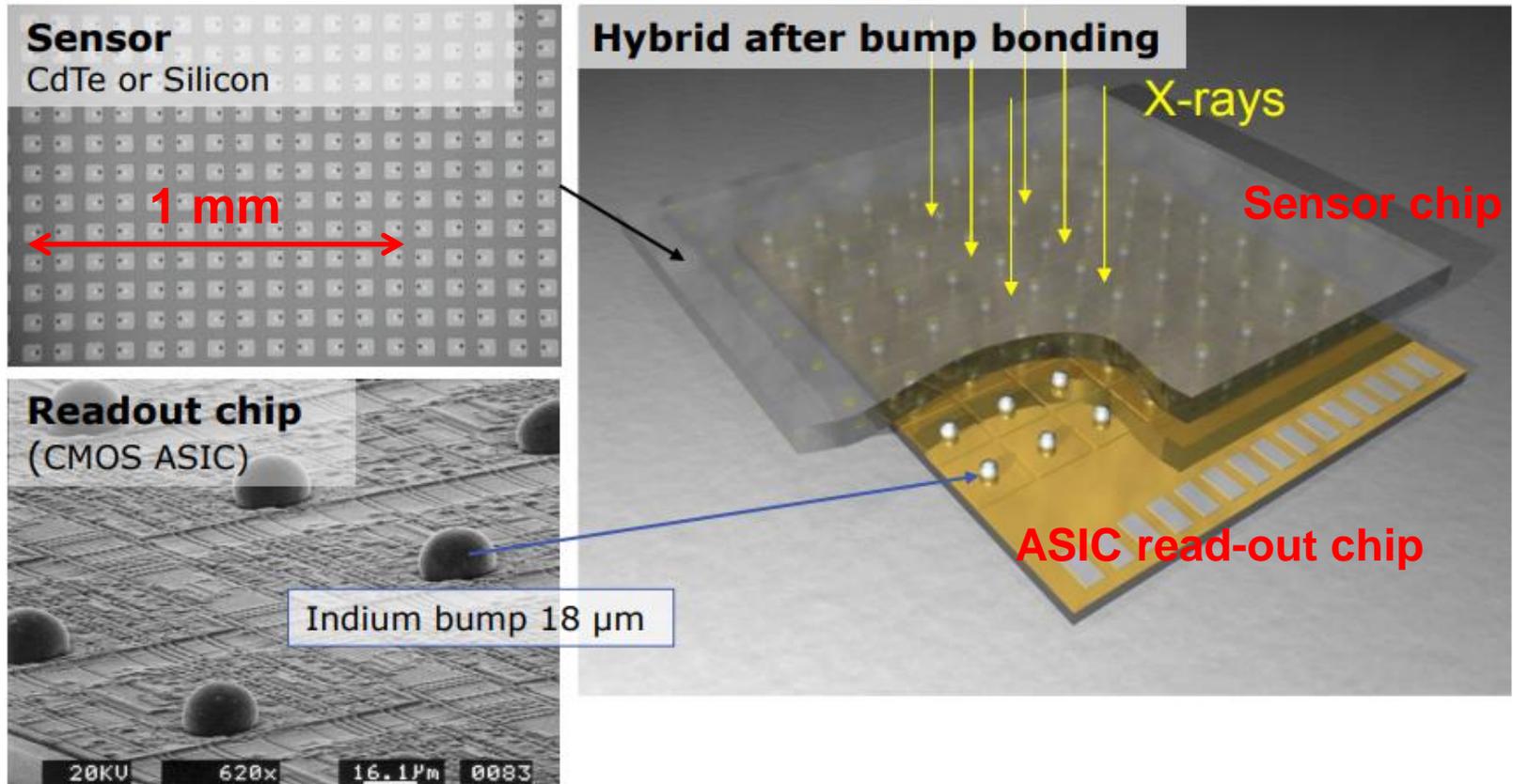
Long narrow electrodes give position just in direction normal to the strips:
Two planes to reconstruct the 2D position

Used in trackers in physics experiments, and in few other applications that need just 1D



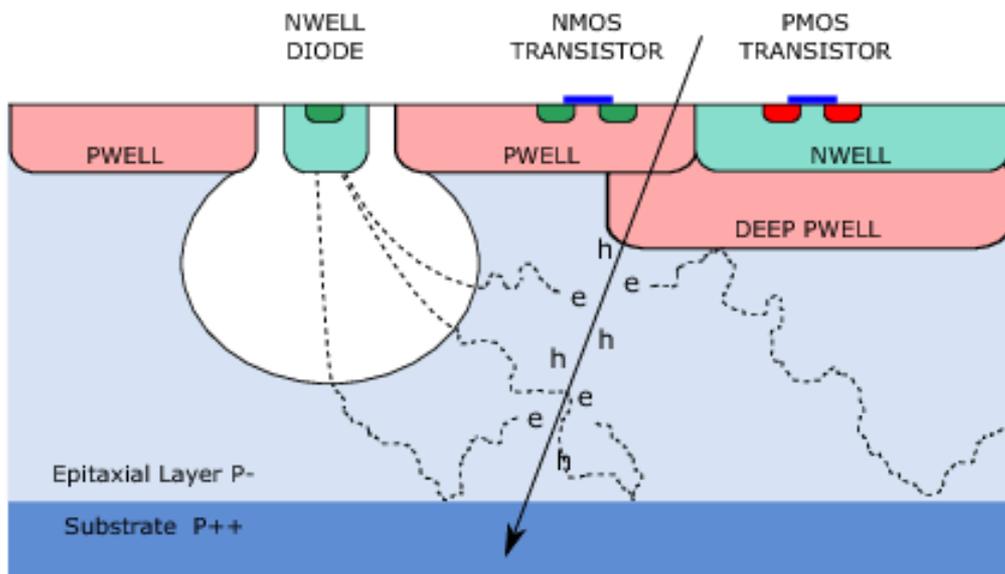
2D read-out: Pixel detector

Hybrid pixel = sensor + readout



Price to pay? N^2 channel w.r.t. $2*N$ of strip sensor

Bump bonding is difficult and expensive → go for a pixel sensor on a chip!!



The sensor is integrated in the same substrate of the electronics.

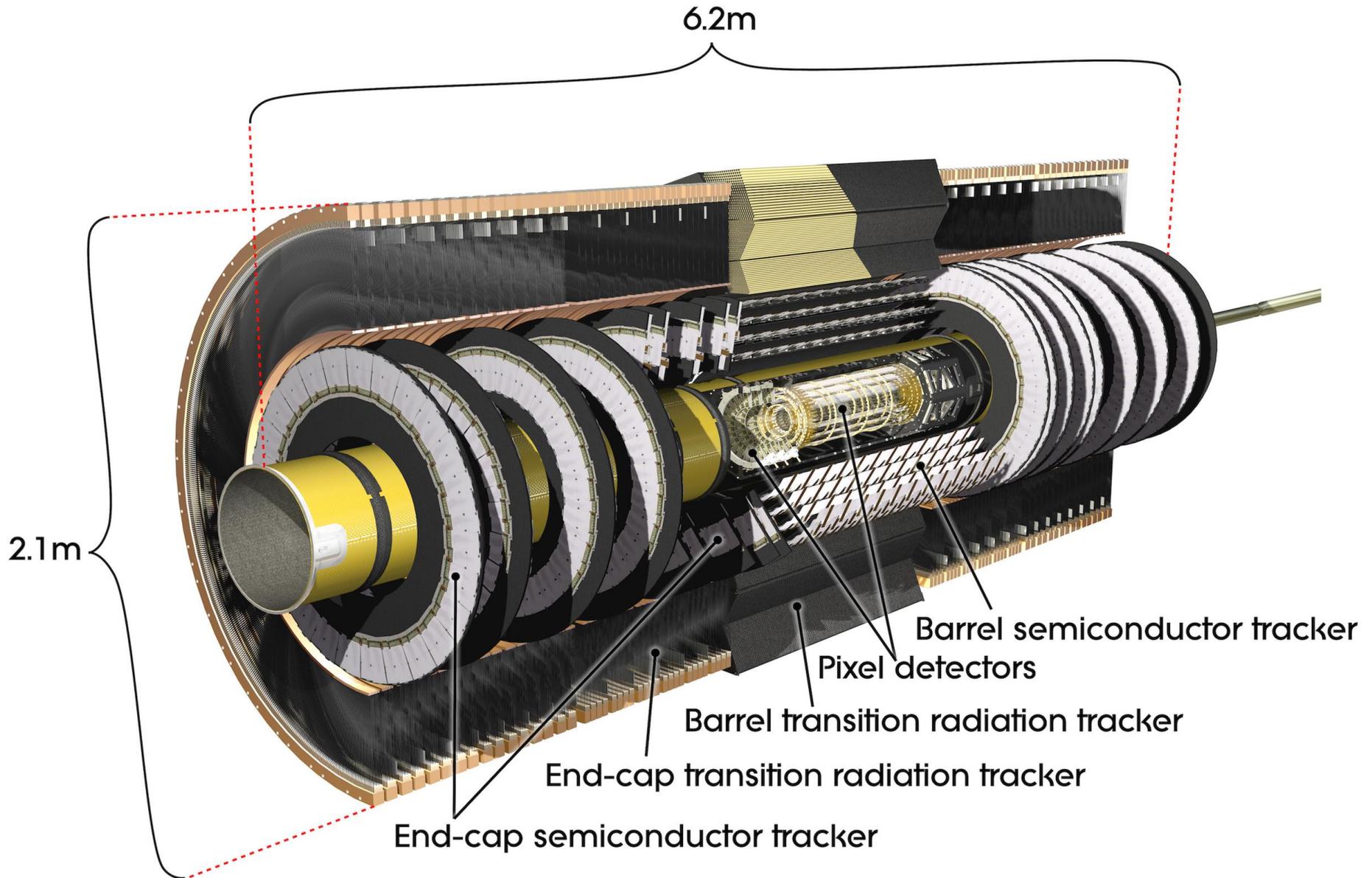
Drawback: the active region is thin (not a problem for mip, problem for X-rays)



Modern trend: Inner tracking system in physics experiment are made of MAPS

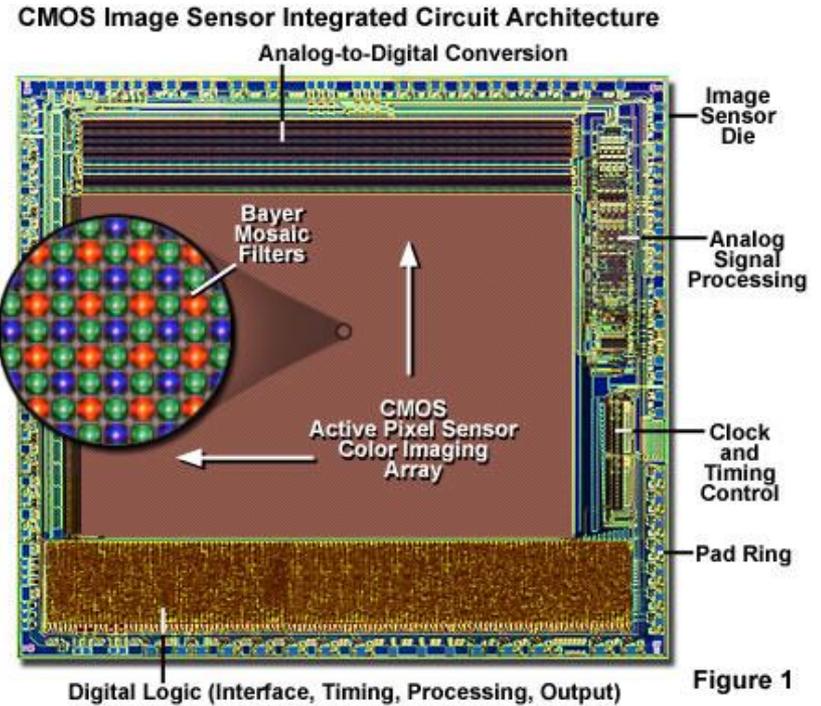
← STAR tracker

ATLAS inner tracking system

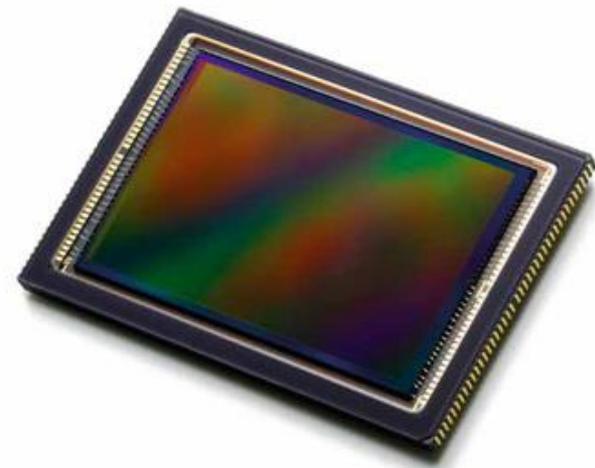
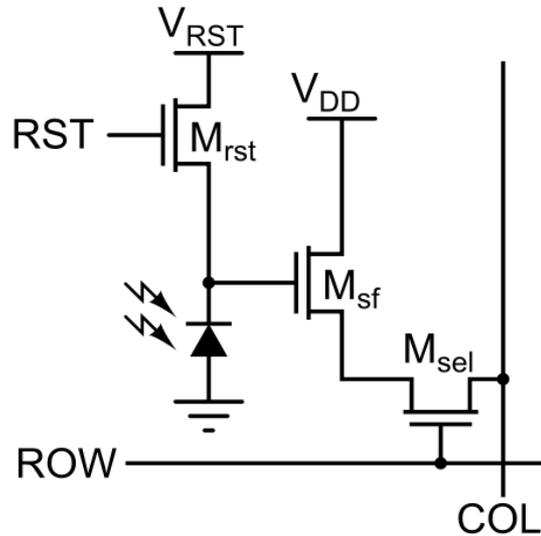


CMOS Cameras

- Array of many small pixels ($\sim M$), for visible light detection
- Fabricated in CMOS technology
- Pushed by digital photography



“three-transistor read-out” in each pixel



Charge Coupled Devices



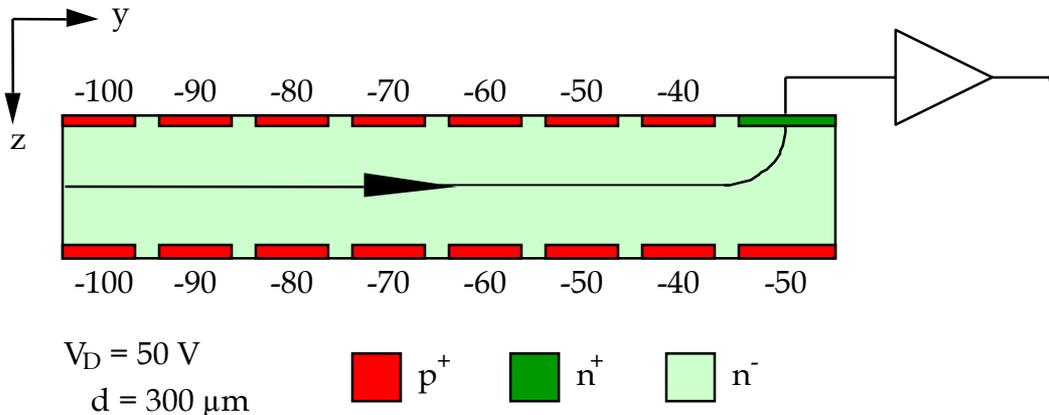
Willard S. Boyle and George E. Smith developed the charge-coupled device in 1969 while working at Bell Laboratories



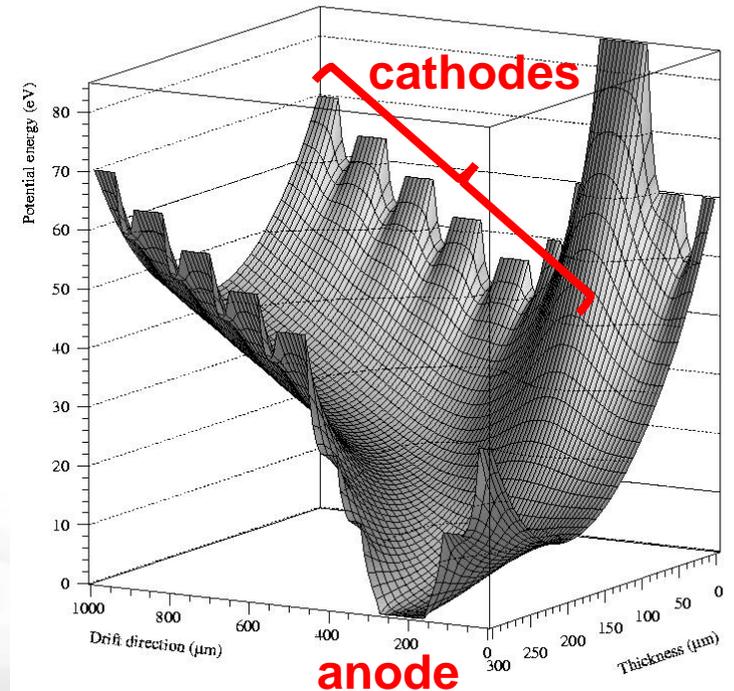
Silicon Drift Detectors

Invented at BNL in 1984

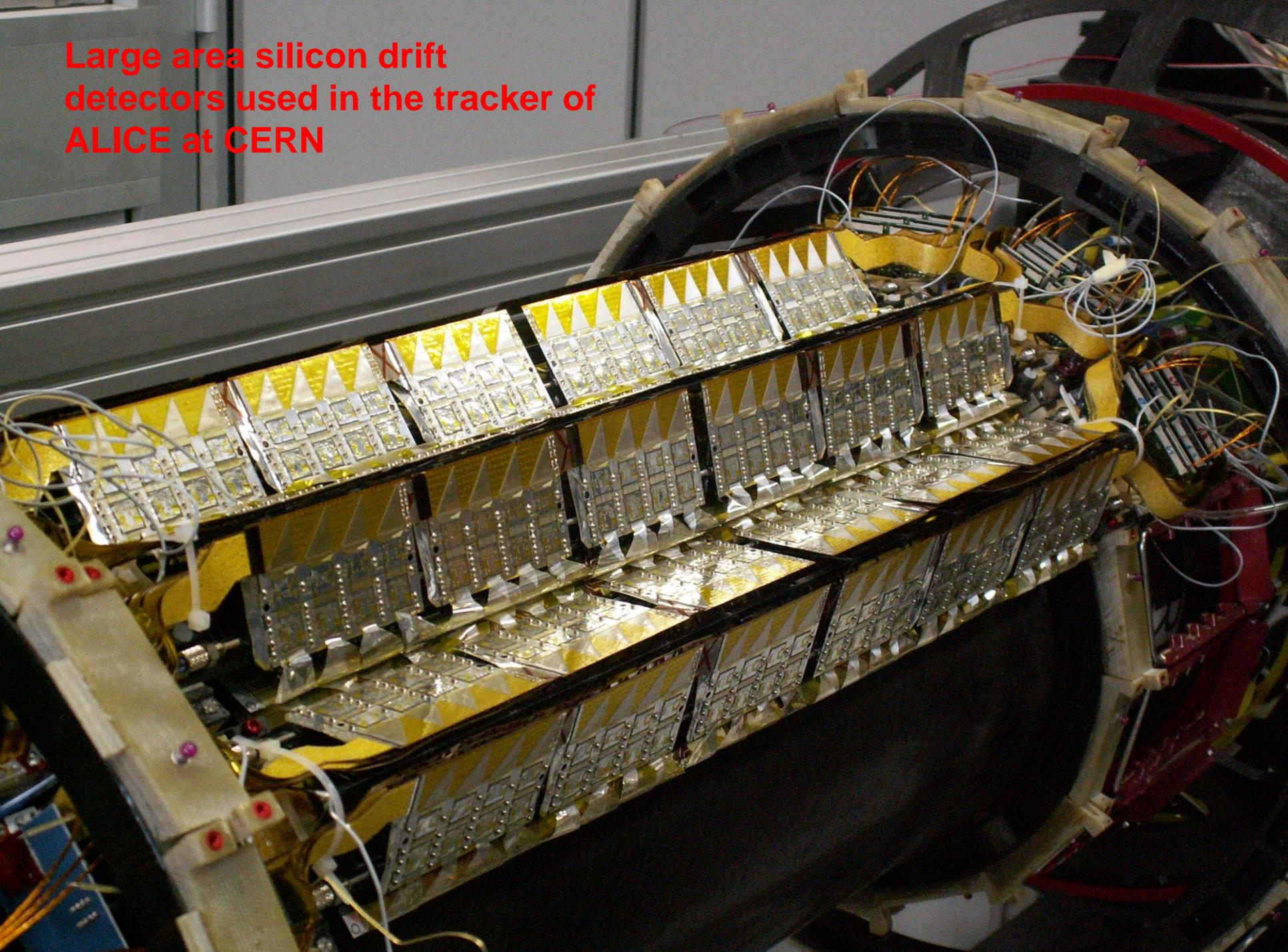
It is possible to deplete the substrate by means of a point-like anode. Anode connected to ROIC, while voltages applied to the cathodes create an electric field following which the electrons drift to and are collected by the anode. No matter how large the area is, the anode is small and so the capacitance and the noise.



Electrostatic potential

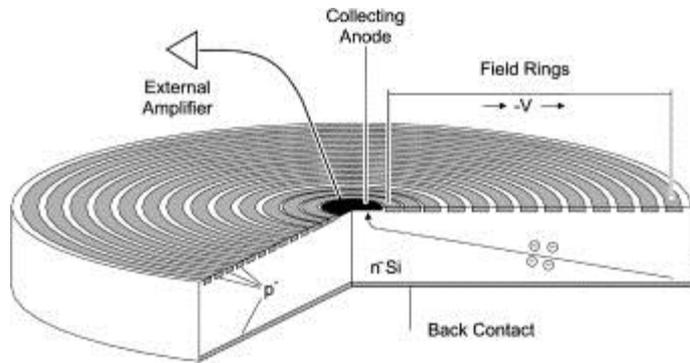


Large area silicon drift detectors used in the tracker of ALICE at CERN



Silicon Drift Detectors as X-ray spectroscopy detectors

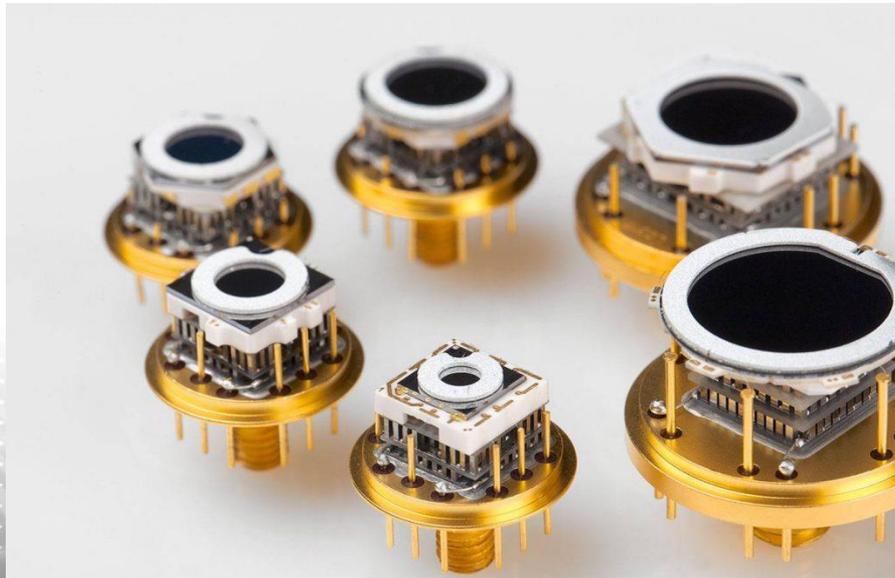
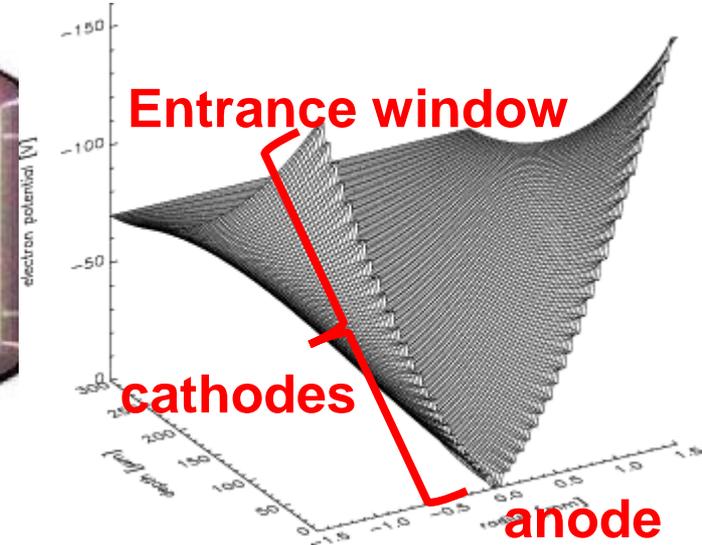
Due to the low capacitance, they have the lowest noise: can detect lowest-energy X-rays



↑ ↑ X-rays enter from the uniform entrance window ↑



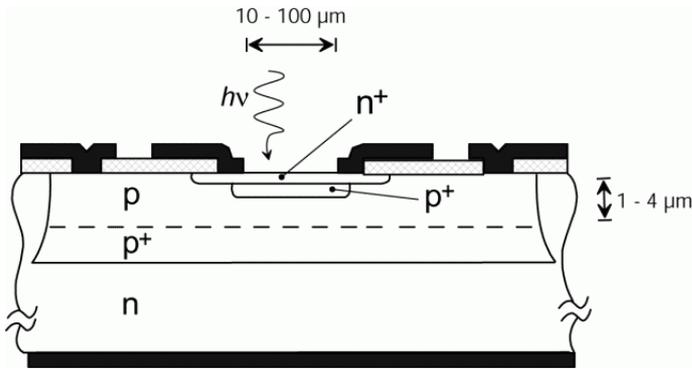
Electrostatic Potential



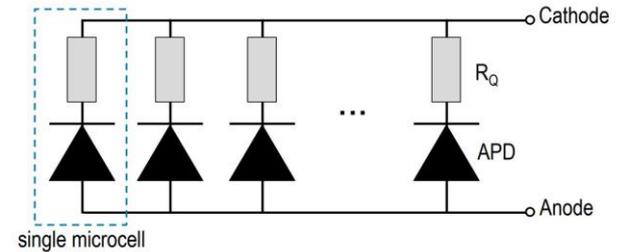
Silicon PhotoMultiplier (SiPM)

Visible photons create just one e-/h+ pair, beyond detection.

But, if **one electron** crosses a high-electric field region, it triggers an avalanche.
Microcells (single Avalanche Photo-Diodes) work above the breakdown voltage.



SiPM structure: array of APDs

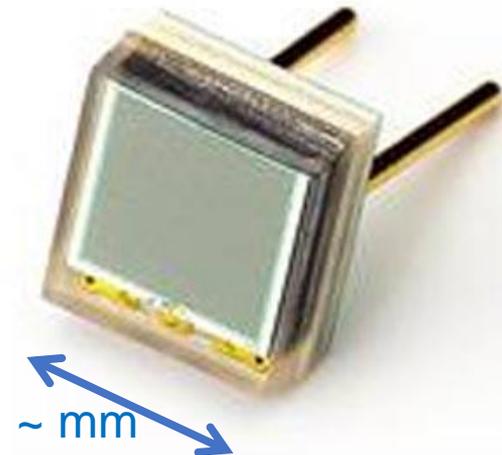
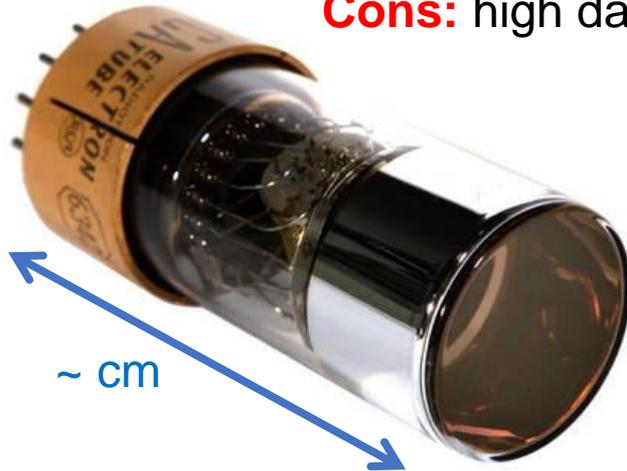


All of the microcells are connected in parallel

Alternative to vacuum photomultiplier tubes for the detection of single visible photons

Pros: smaller, insensitive to magnetic fields, low V, cheap

Cons: high dark count rate



Single Photon Detection

A signal is induced by just one electron, but it is made by $\sim 1\text{M}$ electrons (i.e. huge gain)

